

INFORMATION DISCLOSURE CITATION FORM FOR PATENT APPLICATION (FORM PTO-1449) (Substitute)		Docket No.: 875.0129.U1(US)	Serial No.: 10/736 809		
		Applicant(s): Lassi Hyvonen	Filing Date: herewith 12/15/03		
			Group: 2832		
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Examiner's Signature: NGUYEN			Date Considered: 10/15/05		
Initial if reference was considered, whether or not citation is in conformance with MPEP. Mark through citation if not considered. Include a copy of this citation form with your next correspondence to the Applicant(s).					